

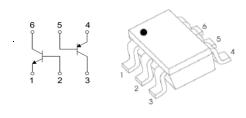


Product data sheet

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SOT-363

Plastic-Encapsulate Transistors

DUAL TRANSISTOR (NPN+PNP)

FEATURES

- Epitaxial Die Construction
- Two isolated NPN/PNP(BC846W+BC856W) Transistors in one package

MAKING: BB

MAXIMUM RATINGS TR1 (T_a=25°C unless otherwise noted)

Symbol	Parameter	Value	Units
V _{CBO}	Collector-Base Voltage	80	V
V _{CEO}	Collector-Emitter Voltage	65	V
V _{EBO}	Emitter-Base Voltage	6	V
lc	Collector Current –Continuous	0.1	А
Pc	Collector Power Dissipation	200	mW
TJ	Junction Temperature	150	°C
T _{stg}	Storage Temperature	-55-150	°C

CHARACTERISTICS of TR1 (NPN Transistor) (Ta=25℃ unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =10μΑ,I _E =0	80			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =10mA,I _B =0	65			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =1µA,I _C =0	6			V
Collector cut-off current	I _{СВО}	V _{CB} =30V,I _E =0			15	nA
Emitter cut-off current	I _{EBO}	V _{EB} =5V,I _C =0			15	nA
DC current gain	h _{FE}	V _{CE} =5V,I _C =2mA	200		450	
	V _{CE(sat)}	I _C =10mA,I _B =0.5mA			0.25	V
Collector-emitter saturation voltage	V _{CE(sat)}	I _C =100mA,I _B =5mA			0.6	V
Page emitter esturation voltage	V _{BE(sat)}	I _C =10mA,I _B =0.5mA		0.7		V
Base-emitter saturation voltage	V _{BE(sat)}	I _C =100mA,I _B =5mA		0.9		V
	V _{BE(on)}	V _{CE} =5V,I _C =2mA	0.58		0.7	V
Base-emitter voltage	V _{BE(on)}	V _{CE} =5V,I _C =10mA			0.72	V
Collector output capacitance	C _{ob}	V _{CB} =10V,I _E =0,f=1MHz			6.0	pF
Transition frequency	f _T	V _{CE} =5V,I _C =10mA,f=100MHz	100			MHz
Noise figure	NF	V _{CE} =5V,I _c =0.2mA, f=1kHz,Rg=2KΩ,∆f=200Hz			10	dB



MAXIMUM RATINGS TR2	(T.=25℃ unless	otherwise noted)
		otherwise noteu)

Symbol	Parameter	Value	Units
V _{CBO}	Collector-Base Voltage	-80	V
V _{CEO}	Collector-Emitter Voltage	-65	V
V _{EBO}	Emitter-Base Voltage	-5	V
lc	Collector Current –Continuous	-0.1	А
Pc∗	Collector Power Dissipation	200	mW
TJ	Junction Temperature	150	°C
T _{stg}	Storage Temperature	-55-150	ç

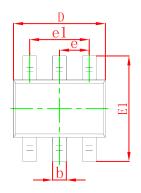
CHARACTERISTICS of TR2 (PNP Transistor) (Ta=25℃ unless otherwise specified)

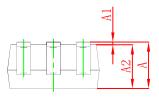
Parameter	Symbol	I Test conditions		ТҮР	MAX	UNIT
Collector-base breakdown voltage	V _{(BR)CBO}	Ι _C =-10μΑ,Ι _E =0	-80			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =-10mA,I _B =0	-65			V
Emitter-base breakdown voltage	V _{(BR)EBO}	Ι _E =-1μΑ,Ι _C =0	-5			V
Collector cut-off current	I _{CBO}	V _{CB} =-30V,I _E =0			-15	nA
Emitter cut-off current	I _{EBO}	V _{EB} =-5V,I _C =0			-15	nA
DC current gain	h _{FE1}	V _{CE} =-5V,I _C =-2mA	220		475	
Collector emitter acturation voltage	V _{CE(sat)}	I _C =-10mA,I _B =-0.5mA			-0.3	V
Collector-emitter saturation voltage	V _{CE(sat)}	I _C =-100mA,I _B =-5mA			-0.65	V
Base-emitter saturation voltage	V _{BE(sat)}	I _C =-10mA,I _B =-0.5mA		-0.7		V
Dase-emilier saturation voltage	V _{BE(sat)}	I _C =-100mA,I _B =-5mA			-0.95	V
Page emitter veltere	V _{BE(on)}	V _{CE} =-5V,I _C =-2mA	-0.6		-0.75	V
Base-emitter voltage	V _{BE(on)}	V _{CE} =-5V,I _C =-10mA			-0.82	V
Collector output capacitance	C _{ob}	V _{CB} =-10V,I _E =0,f=1MHz			4.5	pF
Transition frequency	f⊤	V _{CE} =-5V,I _C =-10mA,f=100MHz	100			MHz
Noise figure	NF	$V_{CE}=-5V,I_{c}=-0.2mA,$ f=1kHz,Rg=2K Ω , Δ f=200Hz			10	dB





SOT-363 Package Outline Dimensions

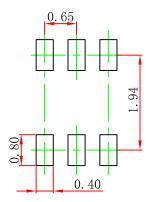




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	0. 20 c	

Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
А	0.900	1.100	0.035	0.043	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.000	0.035	0.039	
b	0.150	0.350	0.006	0.014	
С	0.100	0.150	0.004	0.006	
D	2.000	2.200	0.079	0.087	
E	1.150	1.350	0.045	0.053	
E1	2.150	2.400	0.085	0.094	
e	0.650 TYP		0.026	6 TYP	
e1	1.200	1.400	0.047	0.055	
L	0.525 REF		0.021 REF		
L1	0.260	0.460	0.010	0.018	
θ	0°	8°	0°	8°	

SOT-363 Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:±0.05mm.

3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
BC846PN	SOT-363	3000





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